

NVMFD5483NL

Power MOSFET

60 V, 36 mΩ, 24 A, Dual N-Channel

Features

- Small Footprint (5x6 mm) for Compact Designs
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- 175°C Operating Temperature
- NVMFD5483NLWF – Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- This is a Pb-Free Device

MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter		Symbol	Value	Unit
Drain-to-Source Voltage		V_{DSS}	60	V
Gate-to-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current $R_{\theta JC}$ (Notes 1, 2, 4)	Steady State	$T_C = 25^\circ\text{C}$	I_D 24	A
		$T_C = 100^\circ\text{C}$	17	
Power Dissipation $R_{\theta JC}$ (Notes 1, 2)	Steady State	$T_C = 25^\circ\text{C}$	P_D 44.1	W
		$T_C = 100^\circ\text{C}$	22.1	
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 3 & 4)	Steady State	$T_A = 25^\circ\text{C}$	I_D 6.4	A
		$T_A = 100^\circ\text{C}$	4.5	
Power Dissipation $R_{\theta JA}$ (Notes 1 & 3)	Steady State	$T_A = 25^\circ\text{C}$	P_D 3.1	W
		$T_A = 100^\circ\text{C}$	1.5	
Pulsed Drain Current	$T_A = 25^\circ\text{C}, t_p = 10 \mu\text{s}$	I_{DM}	153	A
Operating Junction and Storage Temperature		T_J, T_{stg}	-55 to 175	$^\circ\text{C}$
Source Current (Body Diode)		I_S	39	A
Single Pulse Drain-to-Source Avalanche Energy ($T_J = 25^\circ\text{C}, V_{GS} = 10 \text{ V}, I_{L(pk)} = 28 \text{ A}, L = 0.1 \text{ mH}$)		E_{AS}	39	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		T_L	260	$^\circ\text{C}$

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case – Steady State (Note 2)	$R_{\theta JC}$	3.4	$^\circ\text{C/W}$
Junction-to-Ambient – Steady State (Note 3)	$R_{\theta JA}$	49	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Surface-mounted to an ideal (infinite) heat sink.
3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
4. Maximum current for pulses as long as 1 second are higher but are dependent on pulse duration and duty cycle.

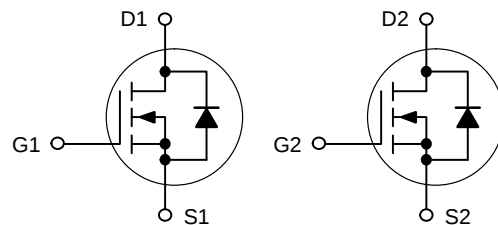


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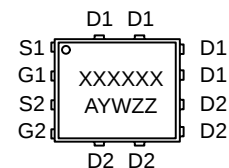
$V_{(BR)DSS}$	$R_{DS(on)}$ MAX	I_D MAX
60 V	36 mΩ @ 10 V	24 A
	45 mΩ @ 4.5 V	

Dual N-Channel



MARKING DIAGRAM

DFN8 5x6
(SO8FL)
CASE 506BT



XXXXXX = 5483NL
(NVMFD5483NL) or
5483LW
(NVMFD5483NLWF)
A = Assembly Location
Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping†
NVMFD5483NLT1G	DFN8 (Pb-Free)	1500/ Tape & Reel
NVMFD5483NLT3G	DFN8 (Pb-Free)	5000/ Tape & Reel
NVMFD5483NLWFT1G	DFN8 (Pb-Free)	1500/ Tape & Reel
NVMFD5483NLWFT3G	DFN8 (Pb-Free)	5000/ Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

NVMFD5483NL

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$	Reference to 25°C $I_D = 250\text{ }\mu\text{A}$		63		mV/ $^\circ\text{C}$
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS} = 0\text{ V},$ $V_{DS} = 60\text{ V}$	$T_J = 25^\circ\text{C}$		1.0	μA
			$T_J = 125^\circ\text{C}$		10	
Gate-to-Source Leakage Current	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = \pm 20\text{ V}$			± 100	nA

ON CHARACTERISTICS (Note 5)

Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\text{ }\mu\text{A}$	1.5		2.5	V
Gate Threshold Voltage Temperature Coefficient	$V_{GS(TH)}/T_J$	Reference to 25°C $I_D = 250\text{ }\mu\text{A}$		-5.2		mV/ $^\circ\text{C}$
Drain-to-Source On Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 15\text{ A}$		29	36	m Ω
		$V_{GS} = 4.5\text{ V}, I_D = 15\text{ A}$		36	45	

CHARGES AND CAPACITANCES

Input Capacitance	C_{iss}	$V_{GS} = 0\text{ V}, f = 1.0\text{ MHz}, V_{DS} = 25\text{ V}$		668		pF
Output Capacitance	C_{oss}			152		
Reverse Transfer Capacitance	C_{rss}			67		
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 10\text{ V}, V_{DS} = 48\text{ V},$ $I_D = 10\text{ A}$		23.4		nC
Threshold Gate Charge	$Q_{G(TH)}$			0.65		
Gate-to-Source Charge	Q_{GS}			2.14		
Gate-to-Drain Charge	Q_{GD}			9.16		
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 4.5\text{ V}, V_{DS} = 48\text{ V}, I_D = 10\text{ A}$		13.2		nC

SWITCHING CHARACTERISTICS (Note 6)

Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = 4.5\text{ V}, V_{DS} = 48\text{ V},$ $I_D = 5.0\text{ A}, R_G = 2.5\text{ }\Omega$		6.8		ns
Rise Time	t_r			10.3		
Turn-Off Delay Time	$t_{d(off)}$			37.5		
Fall Time	t_f			23.5		

DRAIN-SOURCE DIODE CHARACTERISTICS

Forward Diode Voltage	V_{SD}	$V_{GS} = 0\text{ V},$ $I_S = 10\text{ A}$	$T_J = 25^\circ\text{C}$	0.87	1.2	V
			$T_J = 125^\circ\text{C}$	0.82		
Reverse Recovery Time	t_{RR}	$V_{GS} = 0\text{ V}, d_I/d_t = 100\text{ A}/\mu\text{s},$ $I_S = 10\text{ A}$		30		ns
Charge Time	t_a			23.3		
Discharge Time	t_b			6.7		
Reverse Recovery Charge	Q_{RR}			35		nC

5. Pulse Test: pulse width = 300 μs , duty cycle $\leq 2\%$.

6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

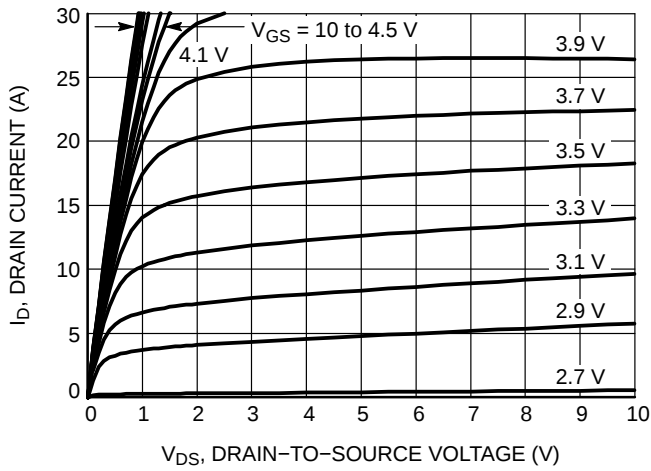


Figure 1. On-Region Characteristics

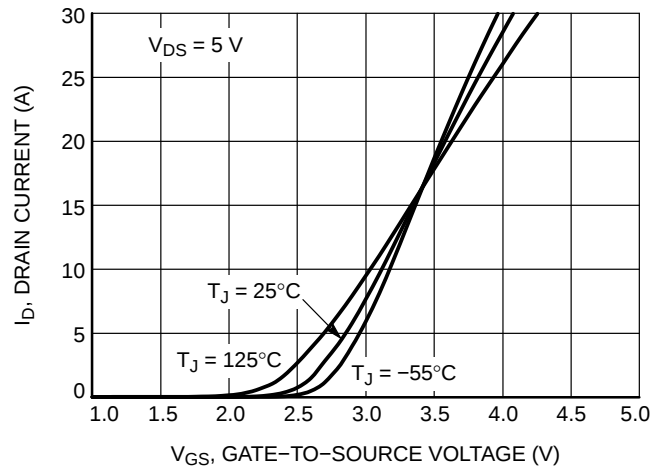


Figure 2. Transfer Characteristics

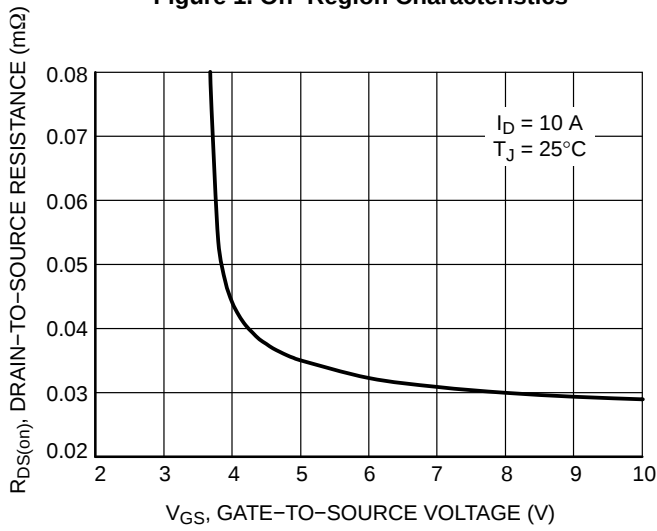


Figure 3. On-Resistance vs. V_{GS}

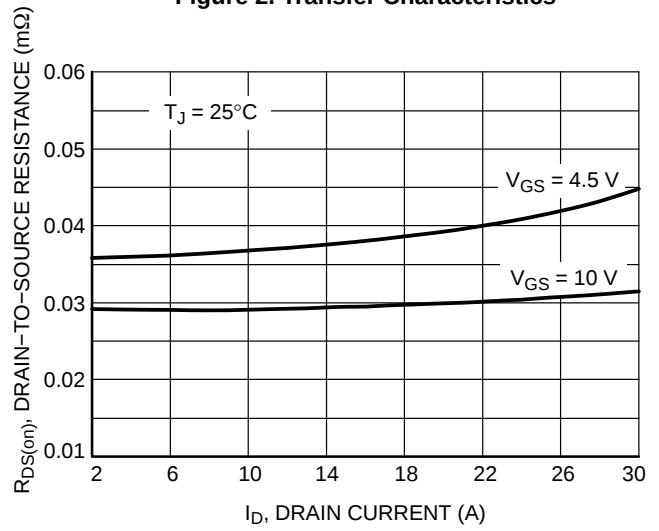


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

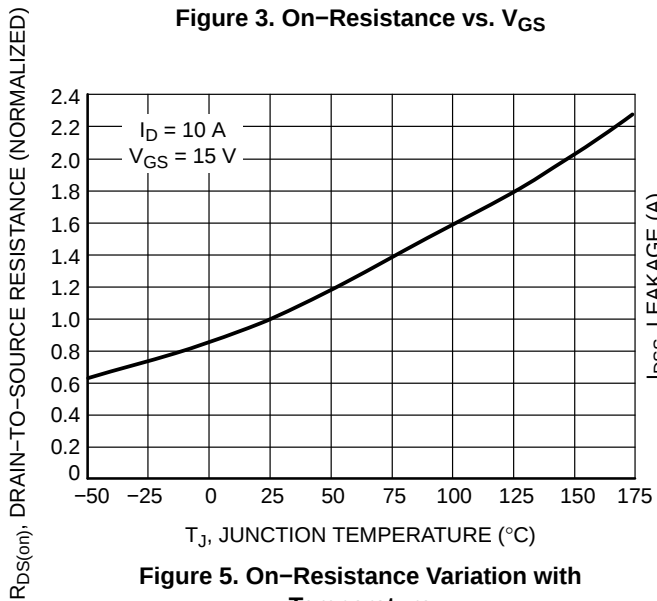


Figure 5. On-Resistance Variation with Temperature

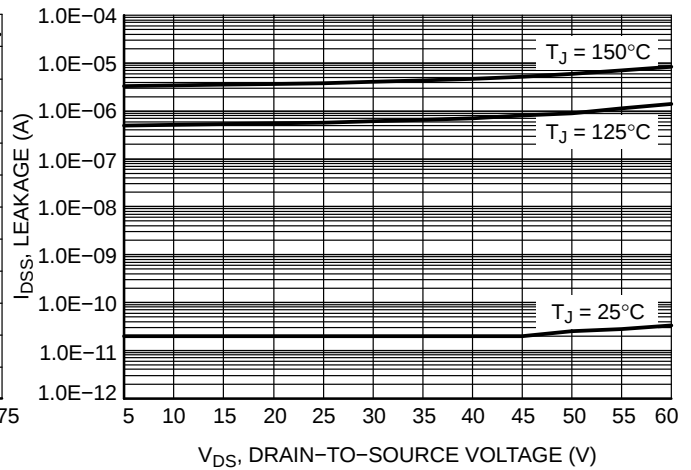


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

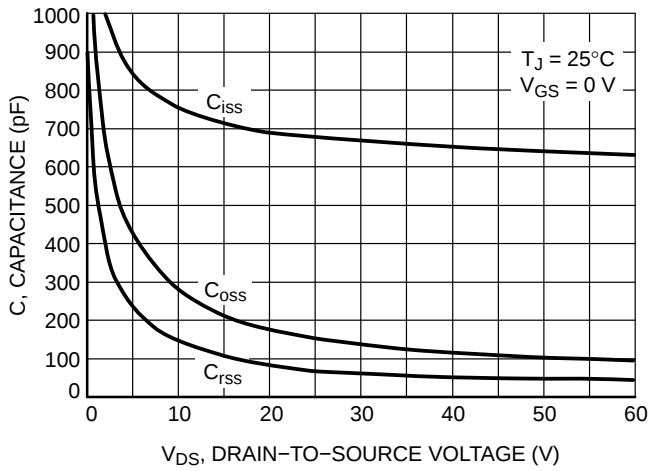


Figure 7. Capacitance Variation

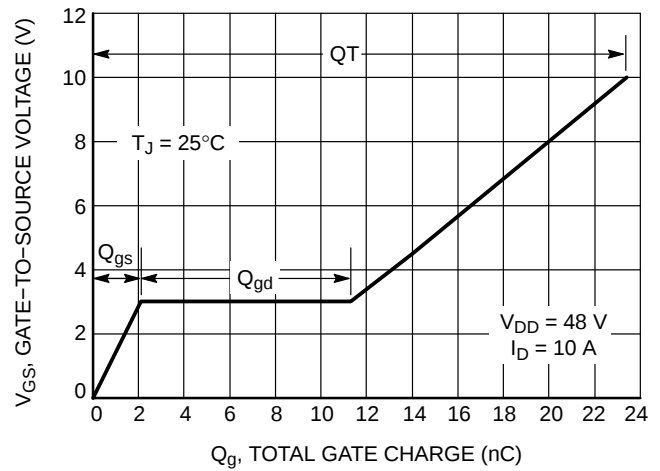


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

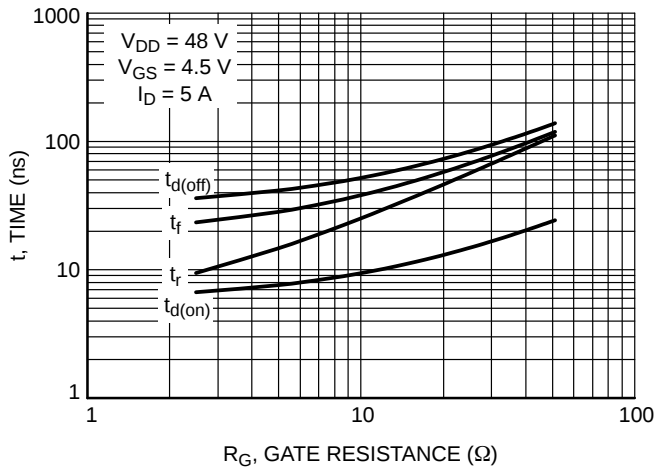


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

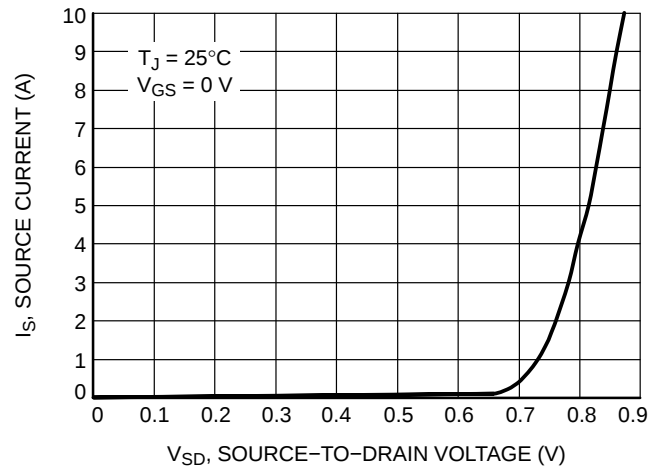


Figure 10. Diode Forward Voltage vs. Current

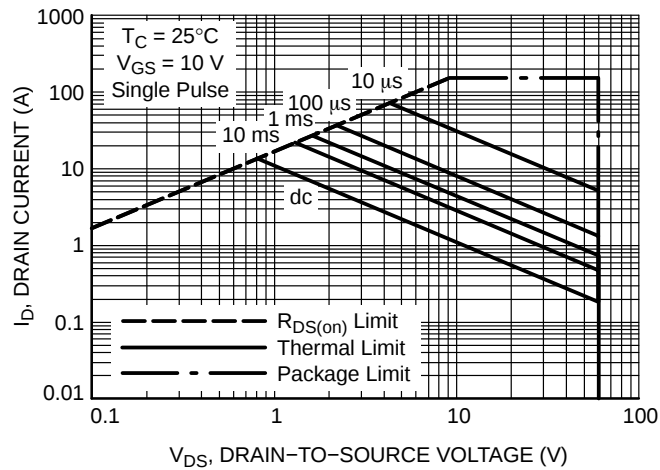


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

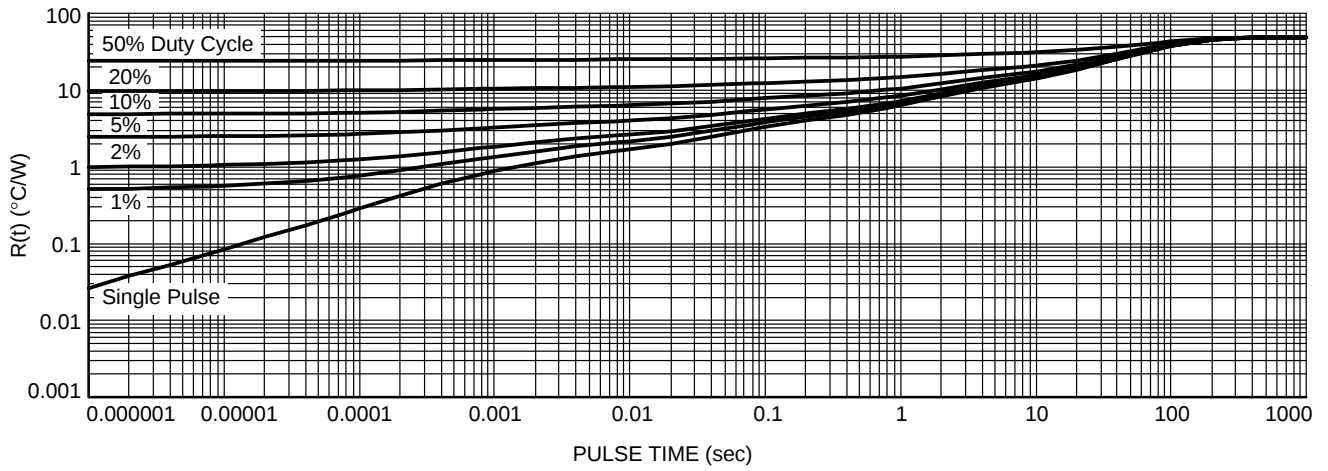


Figure 12. Thermal Response



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Электрон
Связь**

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